Form PTO 1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO. 241723US2S		SERIAL NO. New Application			
(Modified)									
				APPLICANT				_	
LIST OF	REFE	RENCES CITED BY AP	PLICANT	Shigeru NAGASAKA, et al.	IAGASAKA, et al.				
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U.S. PATENT DOCUMENTS									
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE		
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)									
9 00	AW	M. Togo, et al., "Low-Leakage and Highly-Reliable 1.5nm SiON Gate-Dieletric Using Radical Oxynitridation for Sub-0.1μm CMOS", Silicon Systems Research Labs., NEC.C (Japan), 2000 SYMPOSIUM ON VLSI TECHNOLOGY DIGEST OF TECHNICAL PAPERS, 2000, pgs. 116-117							
1. 1/2	AX	Wel-Hua Liu, et al., "A-2 Transistor Source-select (2TS) Flash EEPROM for 1.8V-Only Applications", Semiconductor Technologies Laboratory, Motorola Inc., Austin, Texas, NON-VOLATILE SEMICONDUCTOR MEMORY WORKSHOPS 4.1, 1997, pgs. 1-3							
	AY								
	AZ	Additional References sheet(s) a						sheet(s) attached	
Examiner 2 Date Considered 4/28/0								8/05	
*Examiner: In conformance	*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								